Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/678,061	IMAI ET AL.
Examiner	Art Unit
Chris C. Chu	2815

SEARCHED					
Class	Subclass	Date	Examiner		
257	E21.664, E27.104, 306 & 295	8/11/2006	C.C.		
257	296 & 758	8/11/2006	C.C.		
257	774 & 750	8/11/2006	C.C.		
257	763 & 754	8/11/2006	C.C.		
257	756	8/11/2006	C.C.		
438	238 & 244	8/11/2006	C.C.		
438	003	8/11/2006	C.C.		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
As same	as above	8/11/2006	c.c.		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	8/11/2006	C.C.	
Consulted with J. Jackson	8/10/2006	C.C.	